

Fig. 1. CV/QSCV characteristics for ALD-Al<sub>2</sub>O<sub>3</sub>/Y<sub>2</sub>O<sub>3</sub>/GaAs(001)-4×6 MOSCAPs (a),(d) without UHV annealing, and (b),(e) with UHV annealing. (c),(f) show the characteristics for MBE-YAO/MBE-Y<sub>2</sub>O<sub>3</sub>/GaAs(001)-4×6 MOSCAPs.

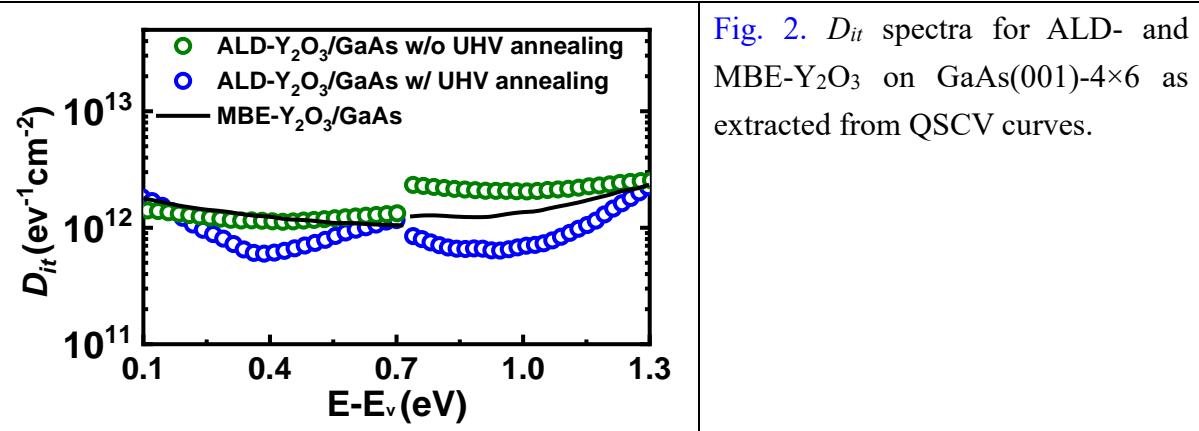


Fig. 2.  $D_{it}$  spectra for ALD- and MBE-Y<sub>2</sub>O<sub>3</sub> on GaAs(001)-4×6 as extracted from QSCV curves.

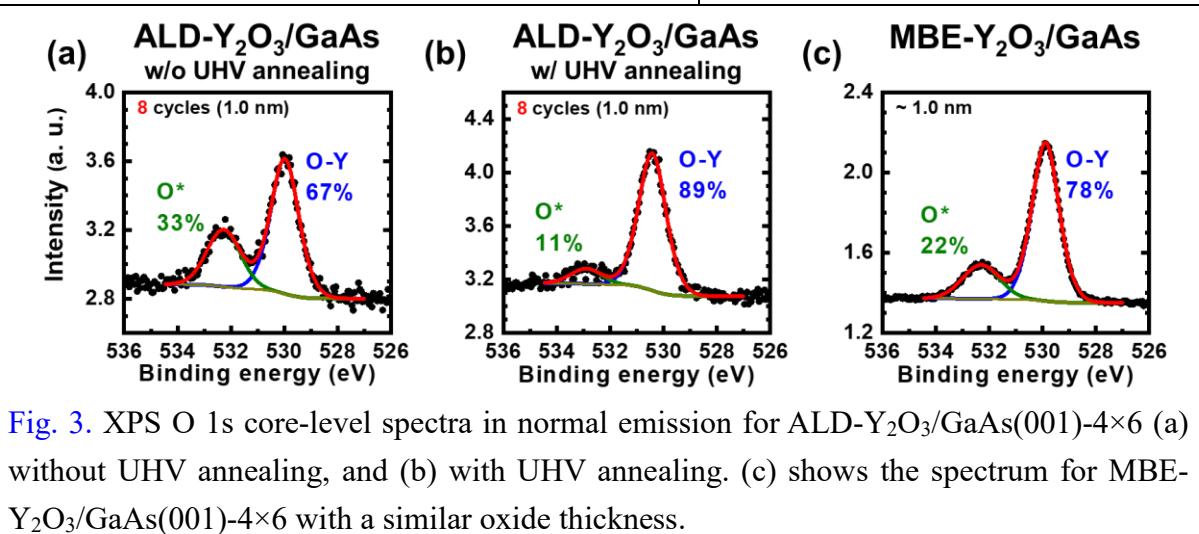


Fig. 3. XPS O 1s core-level spectra in normal emission for ALD-Y<sub>2</sub>O<sub>3</sub>/GaAs(001)-4×6 (a) without UHV annealing, and (b) with UHV annealing. (c) shows the spectrum for MBE-Y<sub>2</sub>O<sub>3</sub>/GaAs(001)-4×6 with a similar oxide thickness.